

Notice of References Cited	Application/Control No. 10/822,789	Applicant(s)/Patent Under Reexamination BHATTACHARYA et al.	
	Examiner Lee, Calvin	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0192082	09-2004	Wagner et al.	439/067
	B	US-2004/0110326	06-2004	Forbes et al.	438/149
	C	US-2005/0042796	02-2005	Wagner, Sigurd	438/065
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	R. Bhattacharya et al, "Island Edge Coverage by Metal Interconnects for Three Dimension Cicuits."
*	V	Wang et al, "Curved Silicon Electronics," Materials Research Society Symp. Proc. Vol. 769 (2003)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.